

INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT  
Form PTO-1449 (Modified)  
(Use several sheets if necessary)

COMPLETE IF KNOWN

Application Number 09/888,002  
Confirmation Number 9049  
Filing Date June 21, 2001  
First Named Inventor Whonchee Lee  
Group Art Unit 3723  
Examiner Name Dung V. Nguyen  
Attorney Docket No. 108298515US3

Sheet 1 of 4

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	U.S. Patent or Application		Name of Patentee or Inventor of Cited Document	Date of Publication or Filing Date of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		NUMBER	Kind Code (if known)			
	AA	U.S. Application No. 09/651,779 (Atty. Docket No. 10829.8515US)		Moore	Filed 08/30/2000	
	AB	U.S. Application No. 09/651,808 (Atty. Docket No. 4373US)		Chopra et al.	Filed 08/30/2000	RECEIVED DEC - 9 2002 TECHNOLOGY CENTER R3700
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	AD	U.S. Application No. 09/887,767 (Atty. Docket No. 10829.8515US2)		Lee et al.	Filed 06/21/2001	
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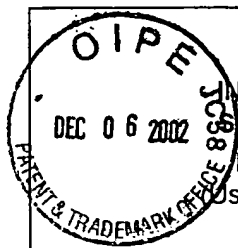
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Sheet 2 of 4

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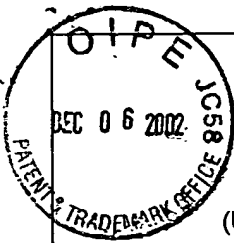
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	CE	WO	00/32356		Talieh	06/08/2000		
	CF	WO	00/59008		Talieh	10/05/2000		
	CG	WO	00/59682		Talieh	10/12/2000		

OTHER PRIOR ART-NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume issue number(s), publisher, city and/or country where published.	T
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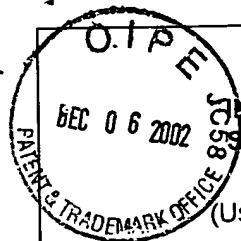
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	CI	BERNHARDT, A.F., CONTOLINI, R.J., MAYER, S.T., "Electrochemical Planarization for Multi-Level Metallization of Microcircuitry," <i>CircuitTree Journal</i> , Vol. 8, No. 10, pp. 38, 40, 42, 44, 46, and 48, Oct. 1995.	
	CJ	HUANG, C.S. et al., "A Novel UV Baking Process to Improve DUV Photoresist Hardness," pp. 135-138.	
	CK	McGraw-Hill, <i>Concise Encyclopedia of Science &amp; Technology</i> , Sybil P. Parker, Editor in Chief, Fourth Edition, p. 367, McGraw-Hill, New York, New York, 1998.	
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	CM	Micro Photonics, Inc., GSM Application Bulletin, "Low load Micro Scratch Tester (MST) for characterisation of thin polymer films," <a href="http://www.microphotonics.com/mstABpoly.html">http://www.microphotonics.com/mstABpoly.html</a> , 7/25/2002, 3 pages.	
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